

## Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5700MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5700.0096	5700	0.0096	1.6830
		V max (V)	138.00	5700.0089	5700	0.0089	1.5550
		V min (V)	102.00	5700.0060	5700	0.0060	1.0597
Limits				5725-5850 MHz			
Result				Complies			

## Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5700MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5700.0095	5700	0.0095	1.6685
		T (°C)	-10	5700.0114	5700	0.0114	2.0065
		T (°C)	0	5700.0075	5700	0.0075	1.3143
		T (°C)	10	5700.0135	5700	0.0135	2.3727
		T (°C)	20	5700.0051	5700	0.0051	0.8867
		T (°C)	30	5700.0105	5700	0.0105	1.8420
		T (°C)	40	5700.0110	5700	0.0110	1.9223
		T (°C)	50	5700.0079	5700	0.0079	1.3774
		T (°C)	60	5700.0110	5700	0.0110	1.9345
		T (°C)	70	5700.0062	5700	0.0062	1.0830
Limits				5725-5850 MHz			
Result				Complies			

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Temperature:	26 °C	Relative Humidity:	54%
Pressure:	101KPa	Test Voltage:	AC 120V/60Hz
Test Mode:	TX (5.8G) Mode Frequency U-NII-3 (5745-5825MHz)		

## Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5745MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5745.01059	5745	0.01059	1.8427
		V max (V)	138.00	5745.00157	5745	0.00157	0.2735
		V min (V)	102.00	5745.00080	5745	0.00080	0.1388
Limits				5725-5850 MHz			
Result				Complies			

## Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5745MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5745.00403	5745	0.00403	0.7006
		T (°C)	-10	5745.01152	5745	0.01152	2.0052
		T (°C)	0	5745.00087	5745	0.00087	0.1516
		T (°C)	10	5745.01076	5745	0.01076	1.8724
		T (°C)	20	5745.00845	5745	0.00845	1.4716
		T (°C)	30	5745.01074	5745	0.01074	1.8700
		T (°C)	40	5745.00436	5745	0.00436	0.7592
		T (°C)	50	5745.00760	5745	0.00760	1.3237
		T (°C)	60	5745.00725	5745	0.00725	1.2618
		T (°C)	70	5745.00090	5745	0.00090	0.1563
Limits				5725-5850 MHz			
Result				Complies			



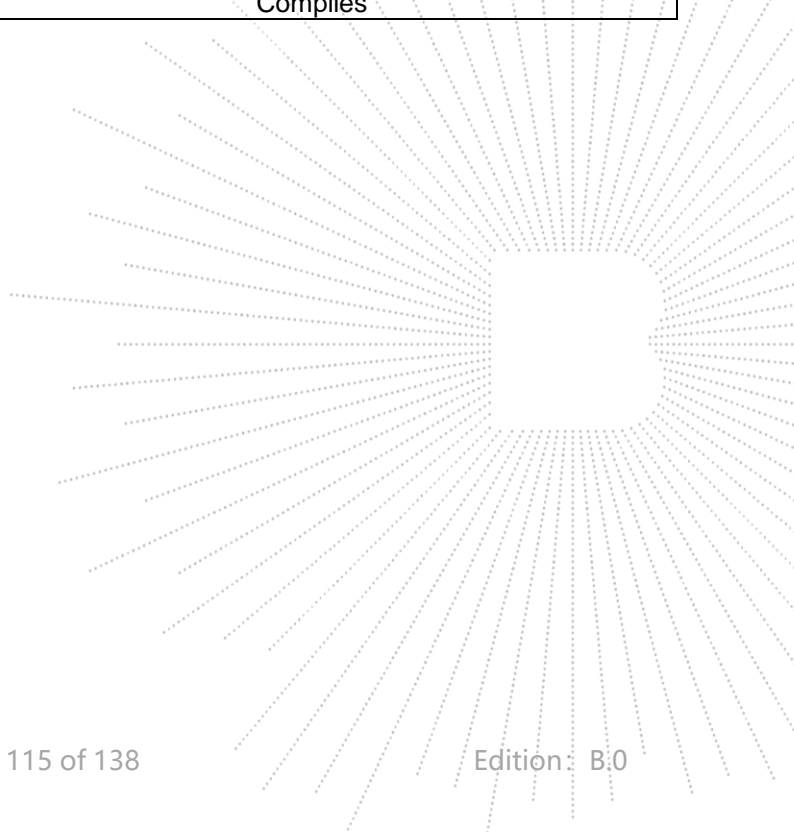
## Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5785MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5785.01347	5785	0.01347	2.3288
		V max (V)	138.00	5785.00625	5785	0.00625	1.0796
		V min (V)	102.00	5785.01066	5785	0.01066	1.8424
Limits				5725-5850 MHz			
Result				Complies			

## Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency: 5785MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5785.01171	5785	0.01171	2.0249
		T (°C)	-10	5785.00747	5785	0.00747	1.2905
		T (°C)	0	5785.00493	5785	0.00493	0.8527
		T (°C)	10	5785.00658	5785	0.00658	1.1376
		T (°C)	20	5785.00242	5785	0.00242	0.4182
		T (°C)	30	5785.00438	5785	0.00438	0.7578
		T (°C)	40	5785.00512	5785	0.00512	0.8852
		T (°C)	50	5785.01295	5785	0.01295	2.2390
		T (°C)	60	5785.00257	5785	0.00257	0.4435
		T (°C)	70	5785.00563	5785	0.00563	0.9740
Limits				5725-5850 MHz			
Result				Complies			

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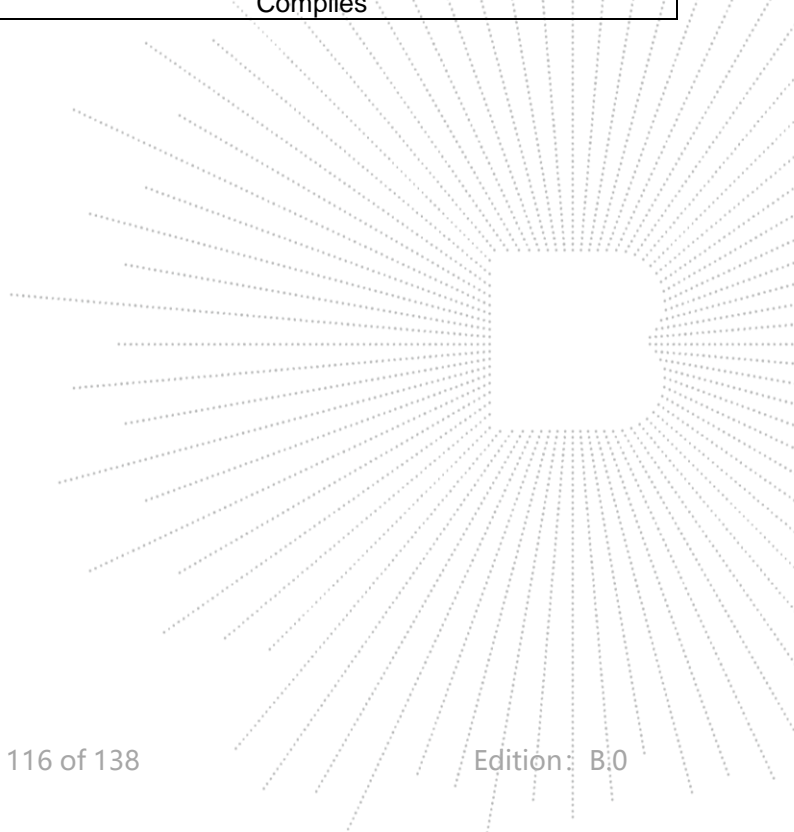
## Voltage vs. Frequency Stability

TEST CONDITIONS				Reference Frequency : 5825MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
T nom (°C)	20	V nom (V)	120.00	5825.00479	5825	0.00479	0.8228
		V max (V)	138.00	5825.00412	5825	0.00412	0.7068
		V min (V)	102.00	5825.01121	5825	0.01121	1.9252
Limits				5725-5850 MHz			
Result				Complies			

## Temperature vs. Frequency Stability

TEST CONDITIONS				Reference Frequency : 5825MHz			
				f	fc	Max. Deviation (MHz)	Max. Deviation (ppm)
V nom (V)	120	T (°C)	-20	5825.00084	5825	0.00084	0.1434
		T (°C)	-10	5825.00190	5825	0.00190	0.3260
		T (°C)	0	5825.00448	5825	0.00448	0.7688
		T (°C)	10	5825.00705	5825	0.00705	1.2109
		T (°C)	20	5825.00382	5825	0.00382	0.6552
		T (°C)	30	5825.01290	5825	0.01290	2.2139
		T (°C)	40	5825.00194	5825	0.00194	0.3331
		T (°C)	50	5825.00574	5825	0.00574	0.9852
		T (°C)	60	5825.00280	5825	0.00280	0.4800
		T (°C)	70	5825.00238	5825	0.00238	0.4094
Limits				5725-5850 MHz			
Result				Complies			

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## 14. Duty Cycle Of Test Signal

### 14.1 Standard Requirement

Pre-analysis Check: While conducting average power measurement, duty cycle of each mode shall be checked to ensure its duty cycle in order to compensate for the loss due to insufficient ratio of duty cycle. All duty cycle is pre-scanned, and result as obtained below shows only the most representative ones where duty cycle is conducted as the given transmission with given virtual operation that expresses the percentage.

### 14.2 Formula

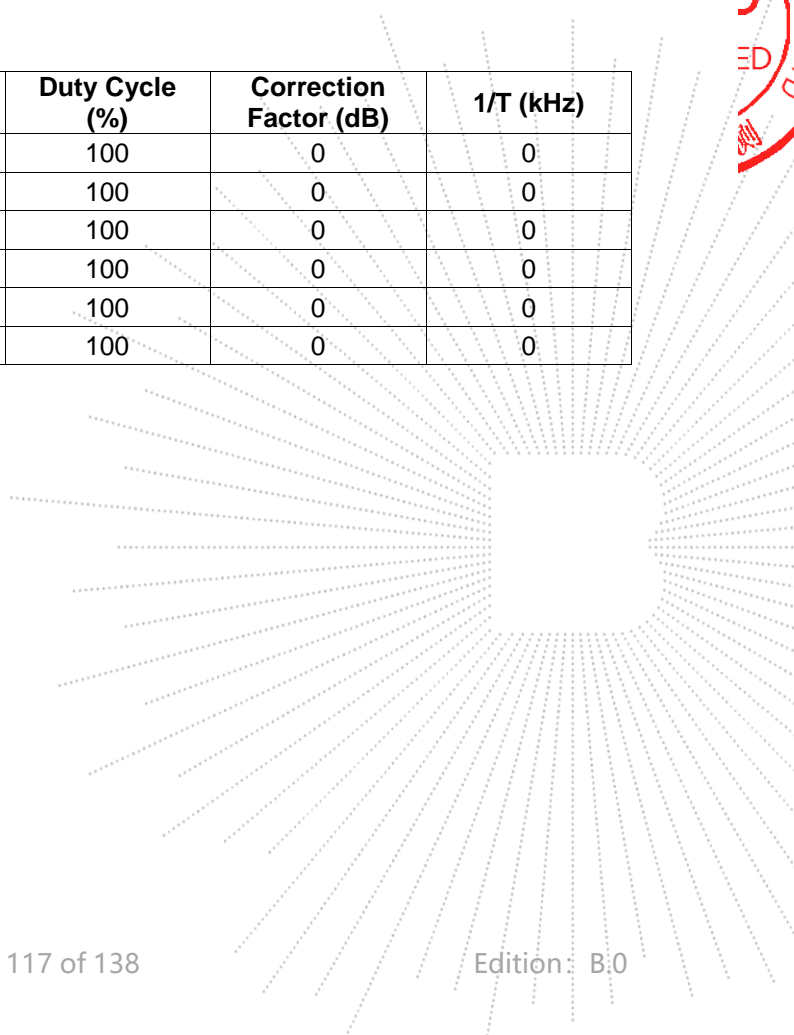
Duty Cycle =  $T_{on} / (T_{on} + T_{off})$

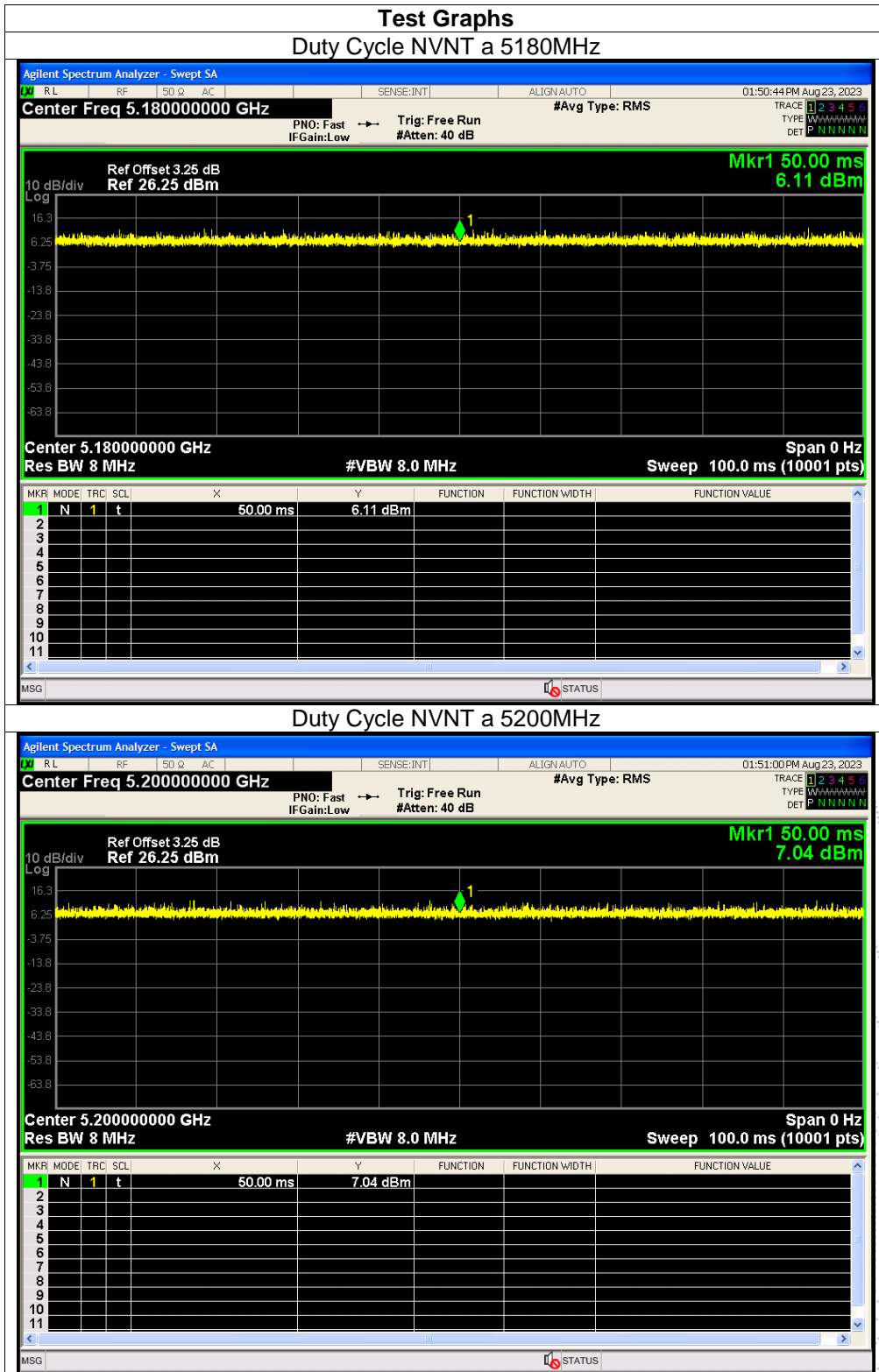
### 14.3 Test Procedure

1. Set span = Zero
2. RBW = 8MHz
3. VBW = 8MHz,
4. Detector = Peak

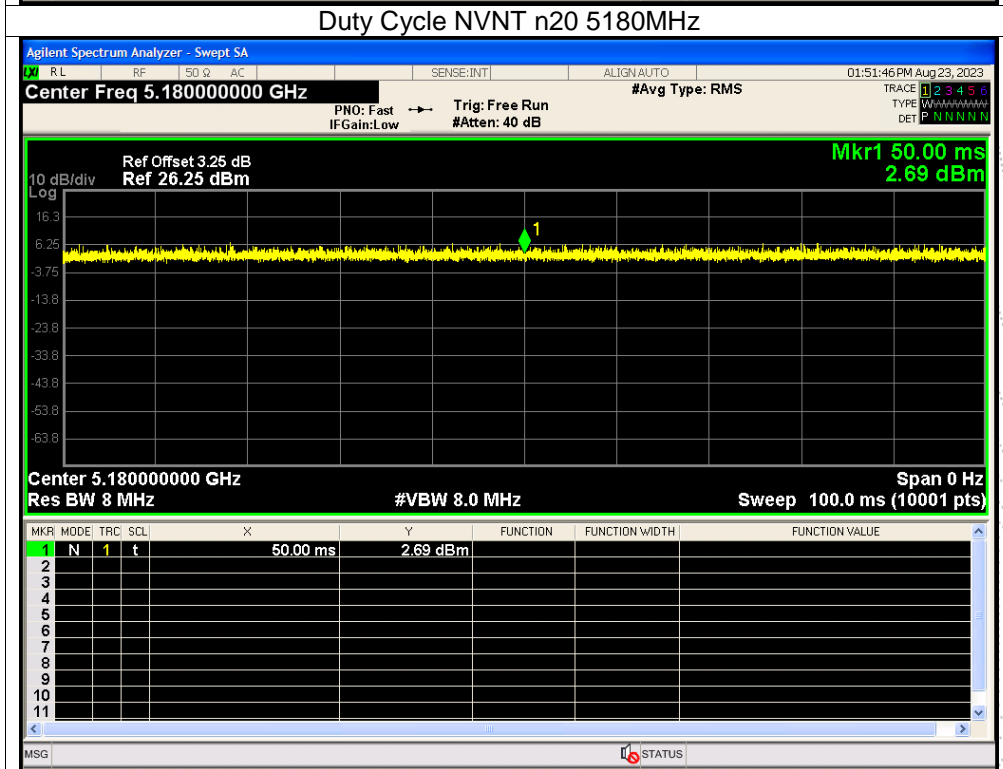
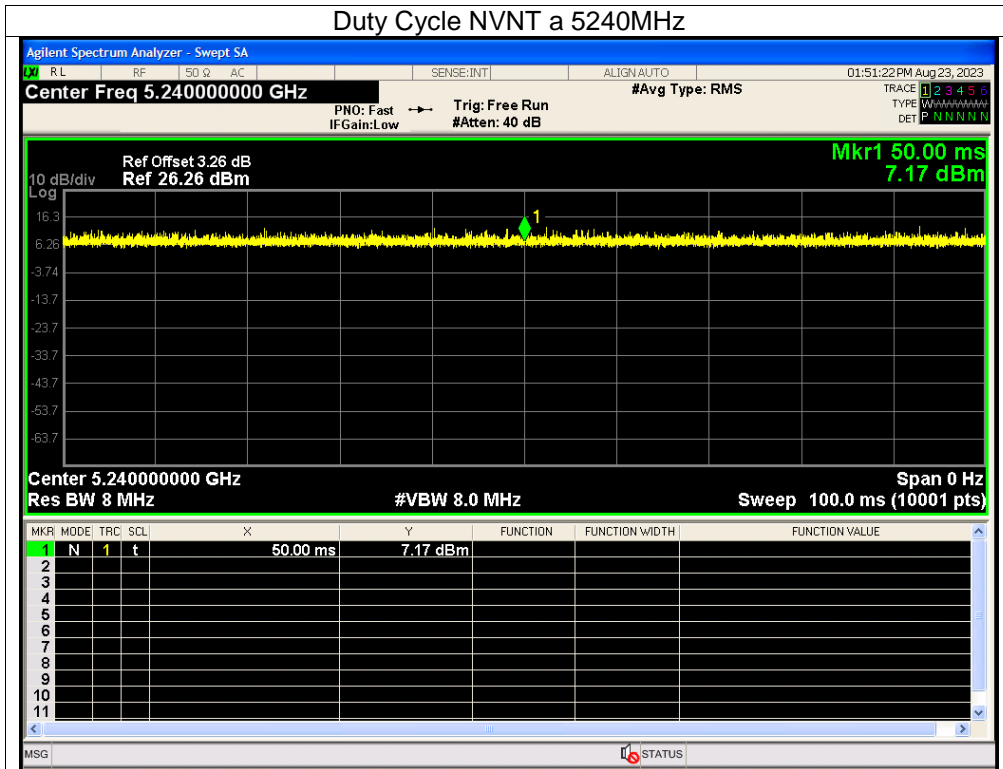
### 14.4 Test Result

Condition	Mode	Frequency (MHz)	Duty Cycle (%)	Correction Factor (dB)	1/T (kHz)
NVNT	a	5180	100	0	0
NVNT	a	5200	100	0	0
NVNT	a	5240	100	0	0
NVNT	n20	5180	100	0	0
NVNT	n20	5200	100	0	0
NVNT	n20	5240	100	0	0

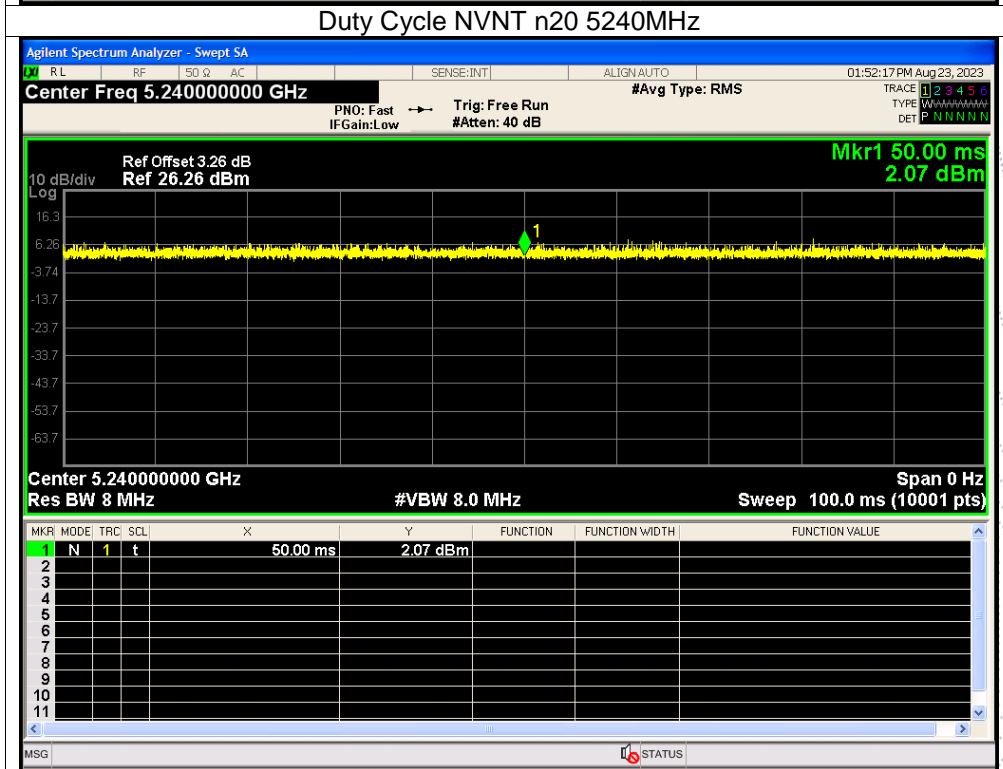
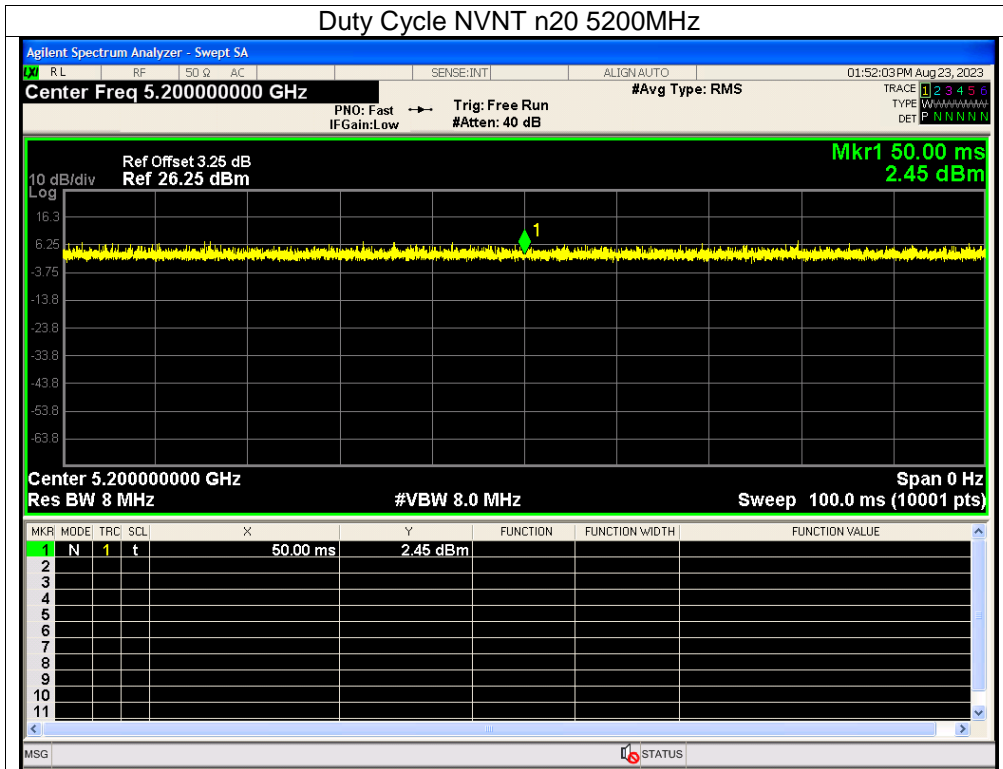




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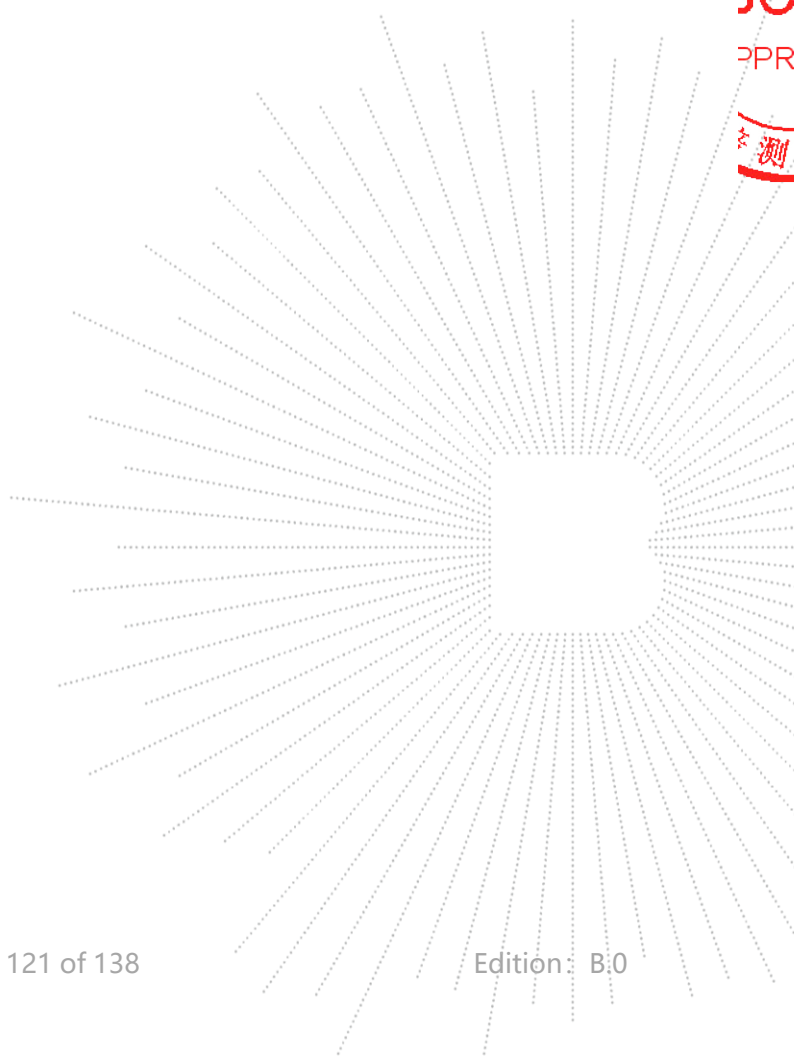
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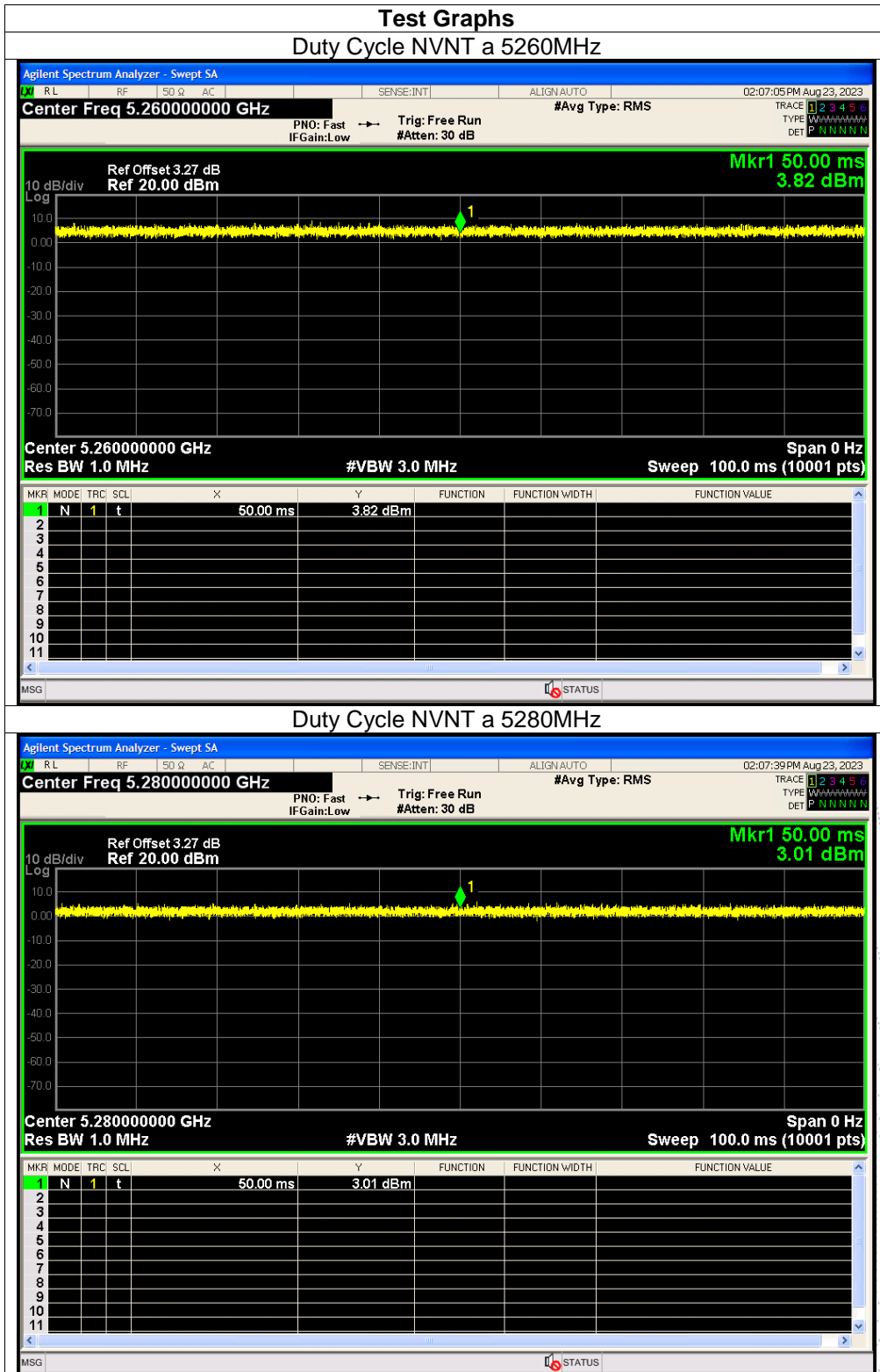




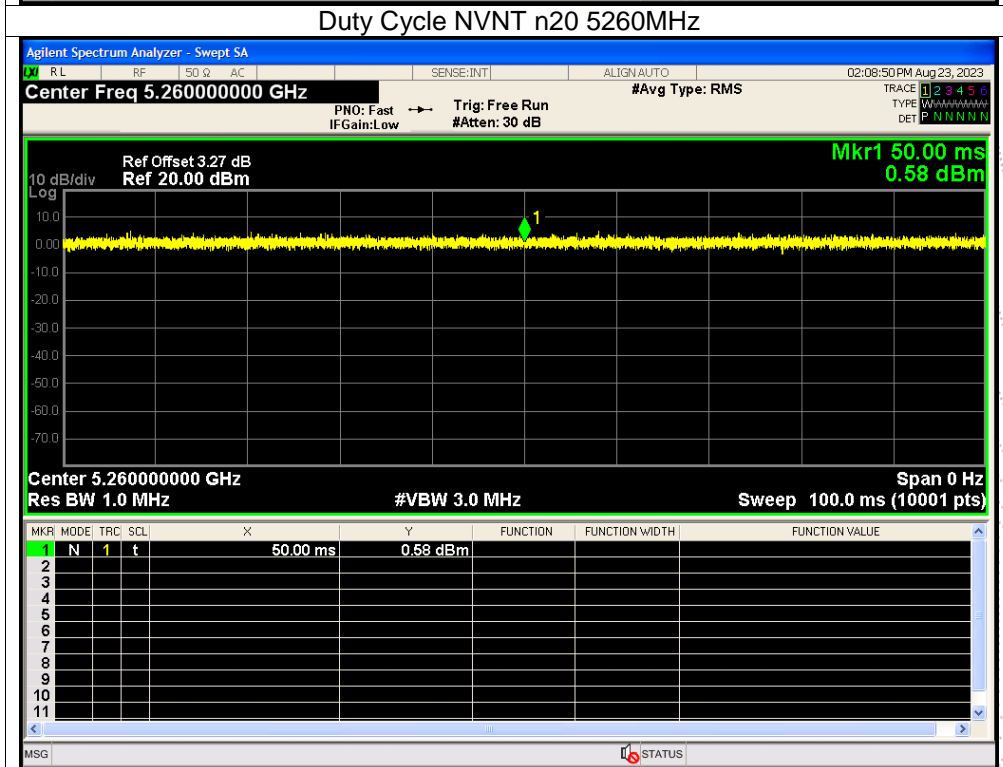
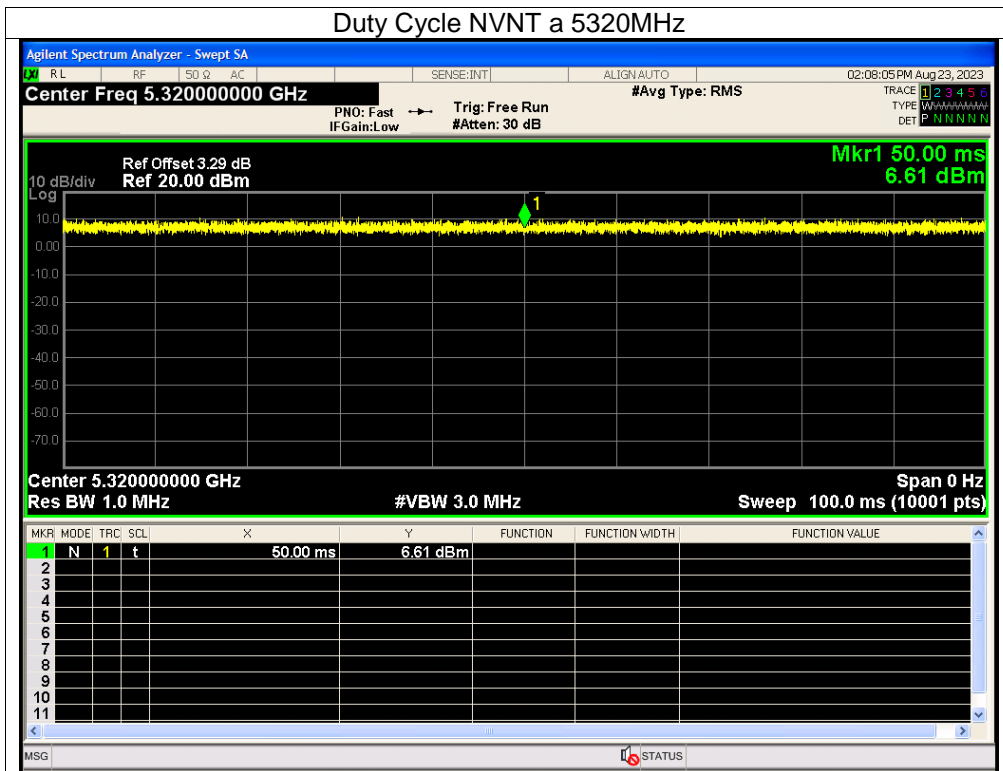
Condition	Mode	Frequency (MHz)	Duty Cycle (%)	Correction Factor (dB)	1/T (kHz)
NVNT	a	5260	100	0	0
NVNT	a	5280	100	0	0
NVNT	a	5320	100	0	0
NVNT	n20	5260	100	0	0
NVNT	n20	5280	100	0	0
NVNT	n20	5320	100	0	0

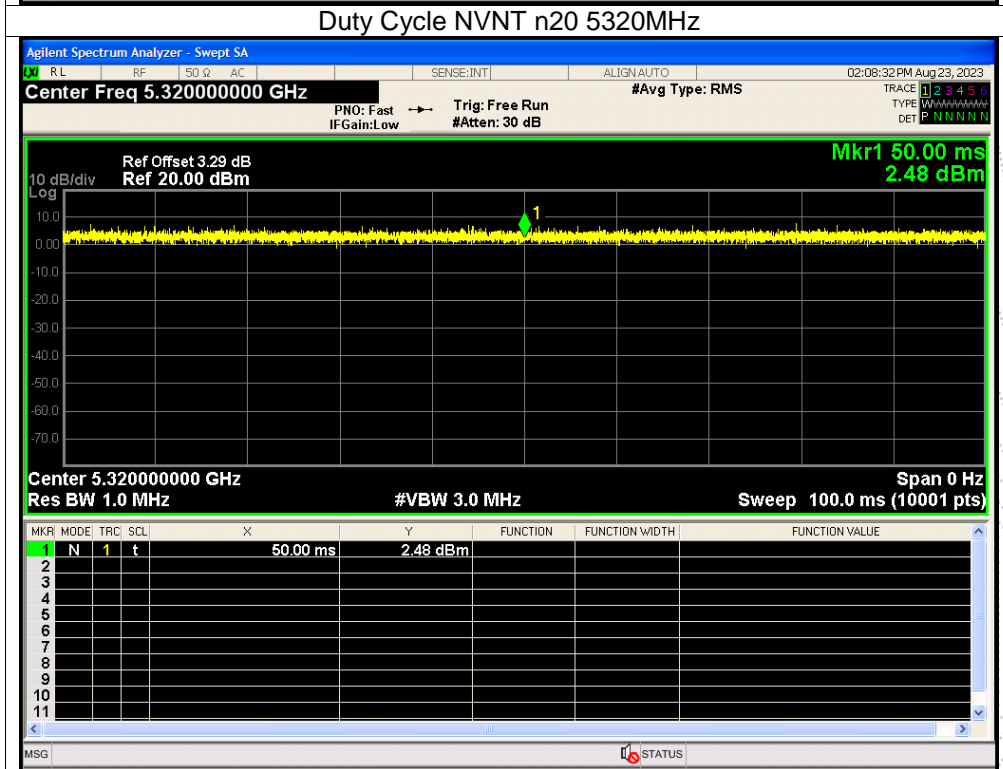
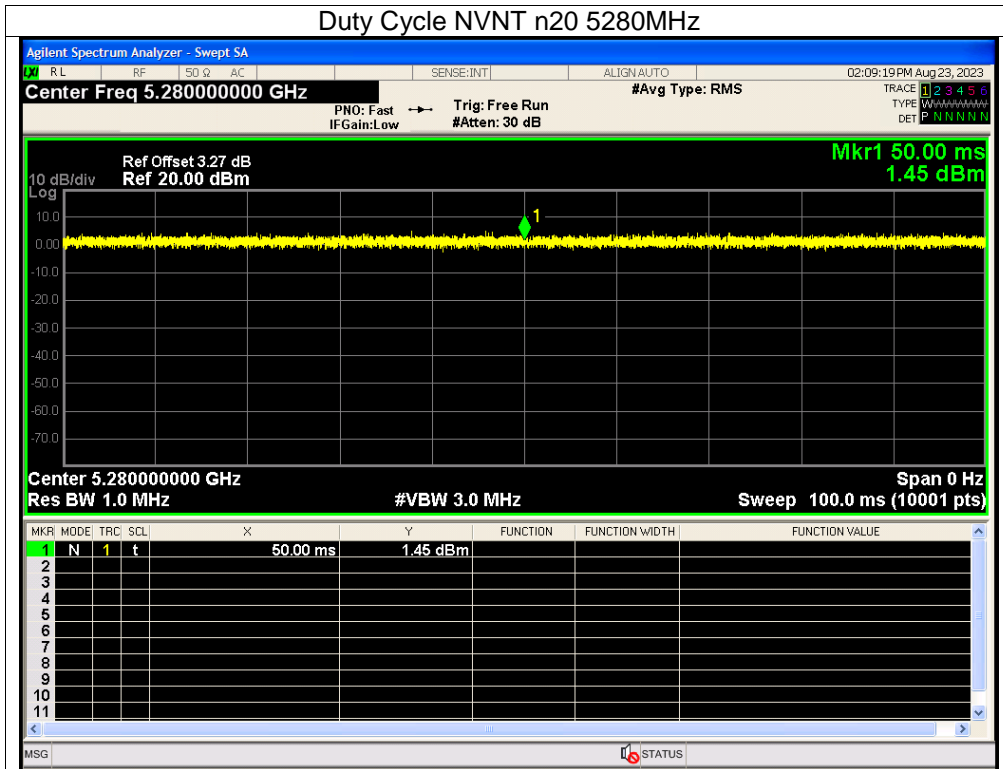
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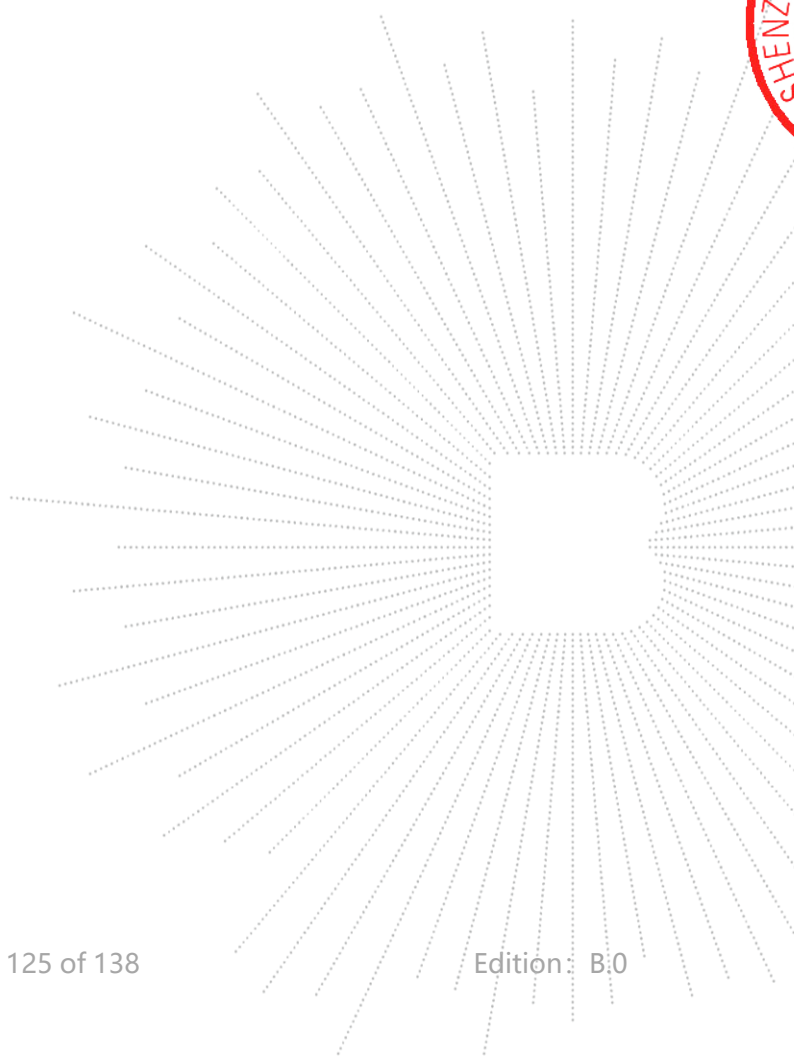
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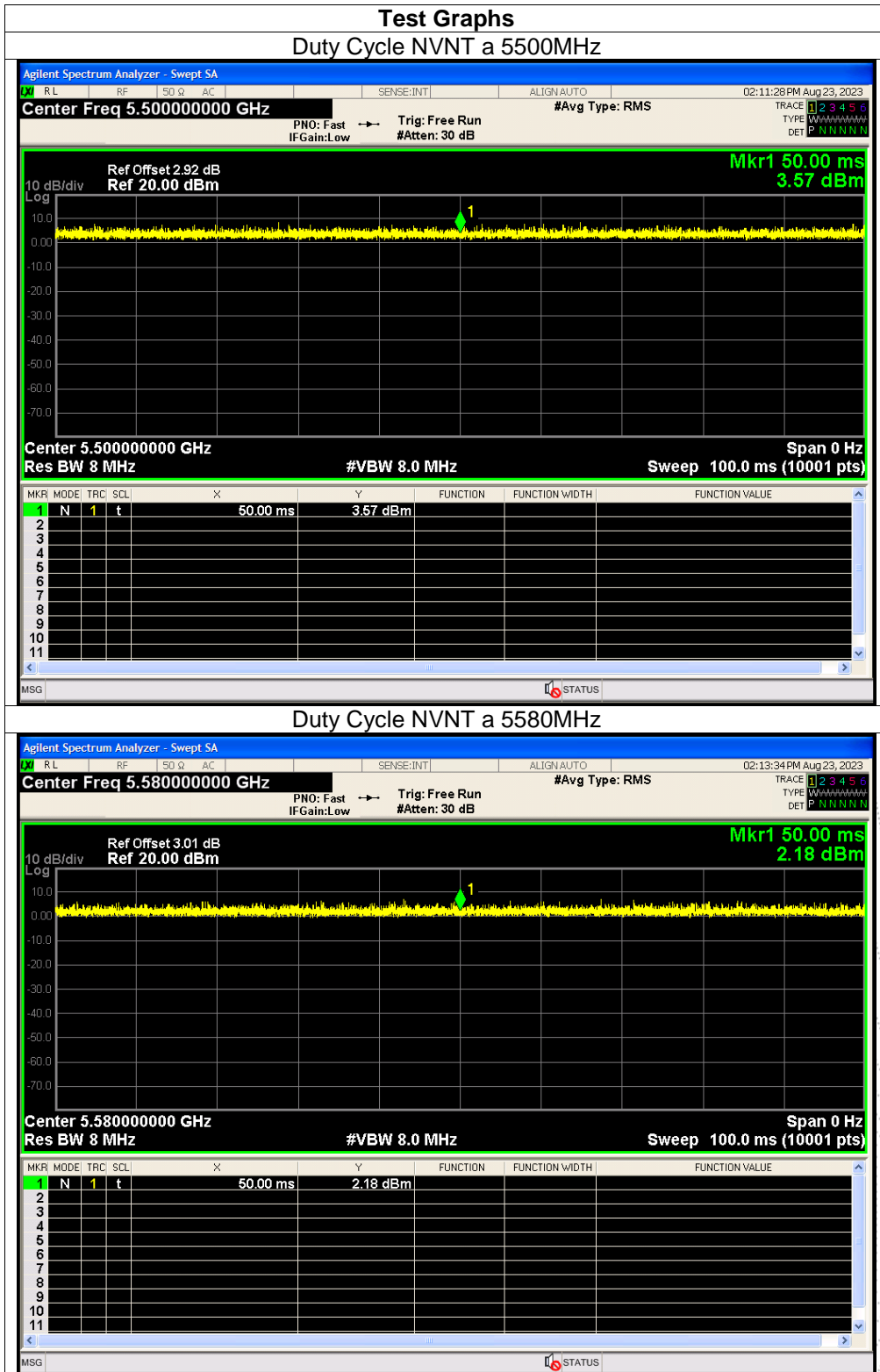


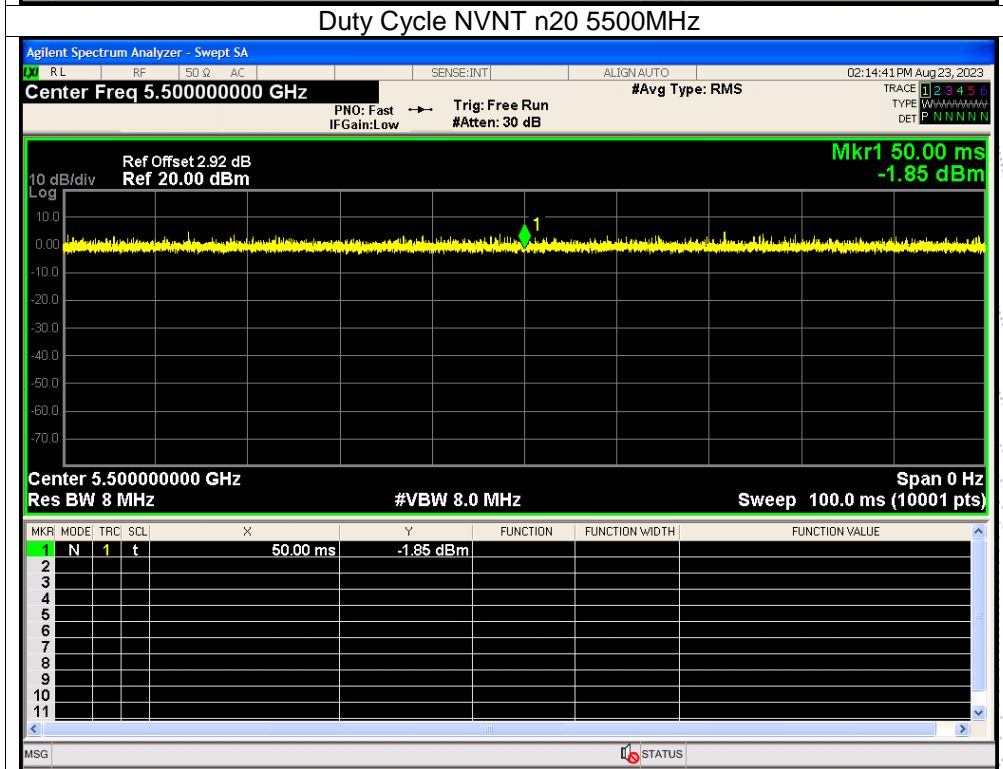
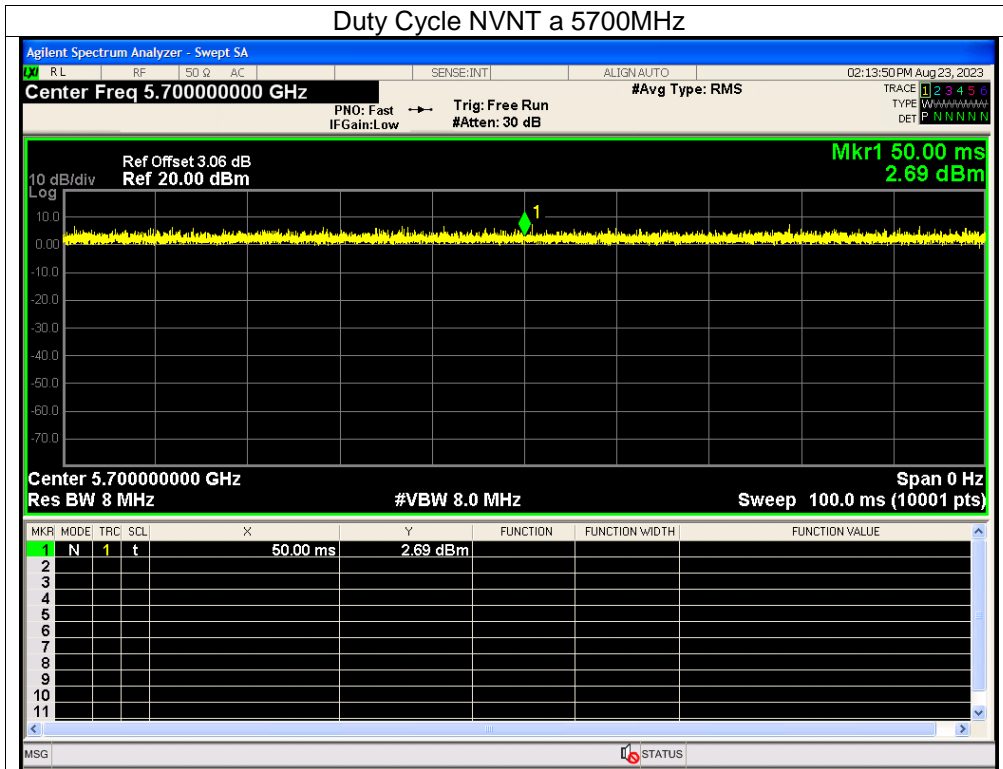


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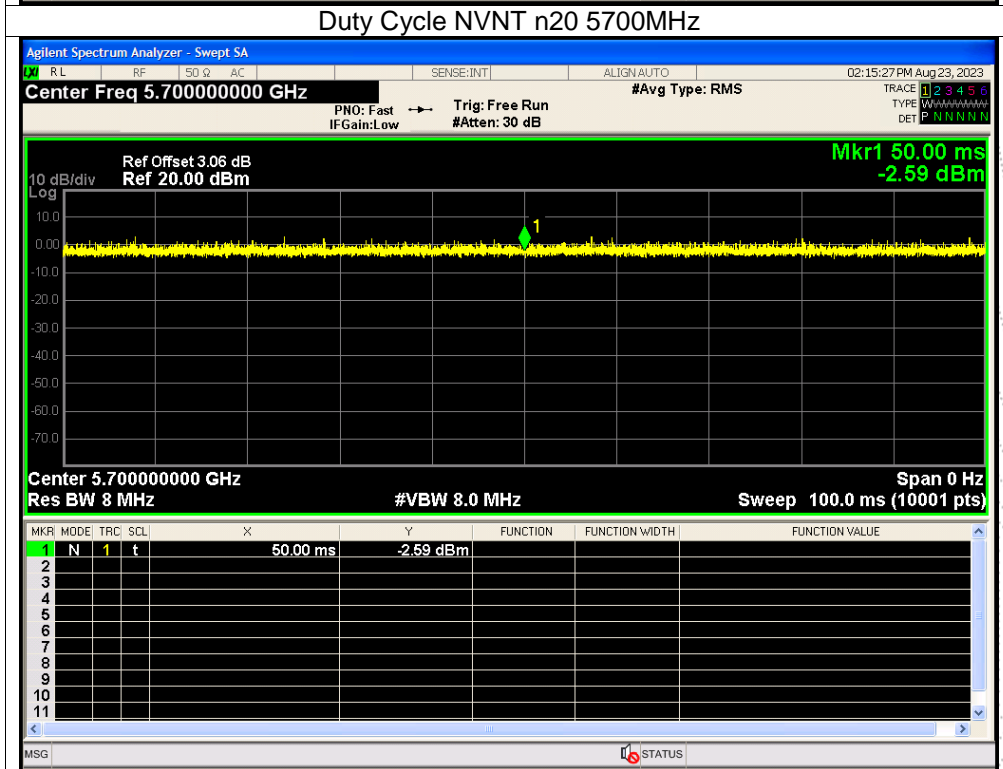
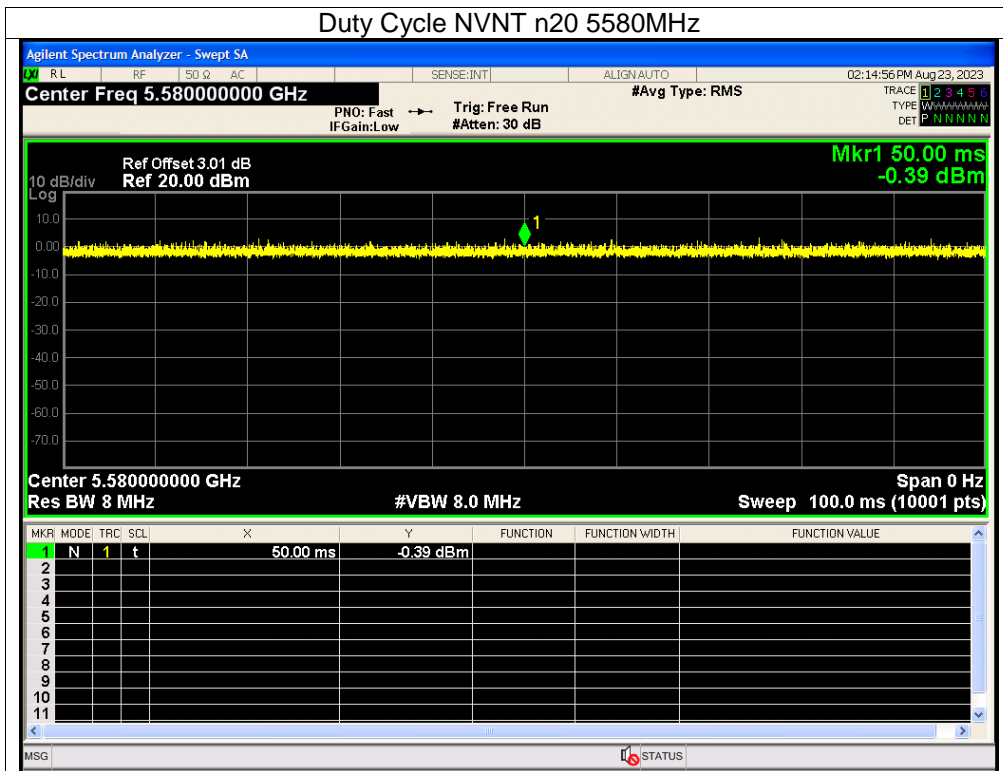
Condition	Mode	Frequency (MHz)	Duty Cycle (%)	Correction Factor (dB)	1/T (kHz)
NVNT	a	5500	100	0	0
NVNT	a	5580	100	0	0
NVNT	a	5700	100	0	0
NVNT	n20	5500	100	0	0
NVNT	n20	5580	100	0	0
NVNT	n20	5700	100	0	0





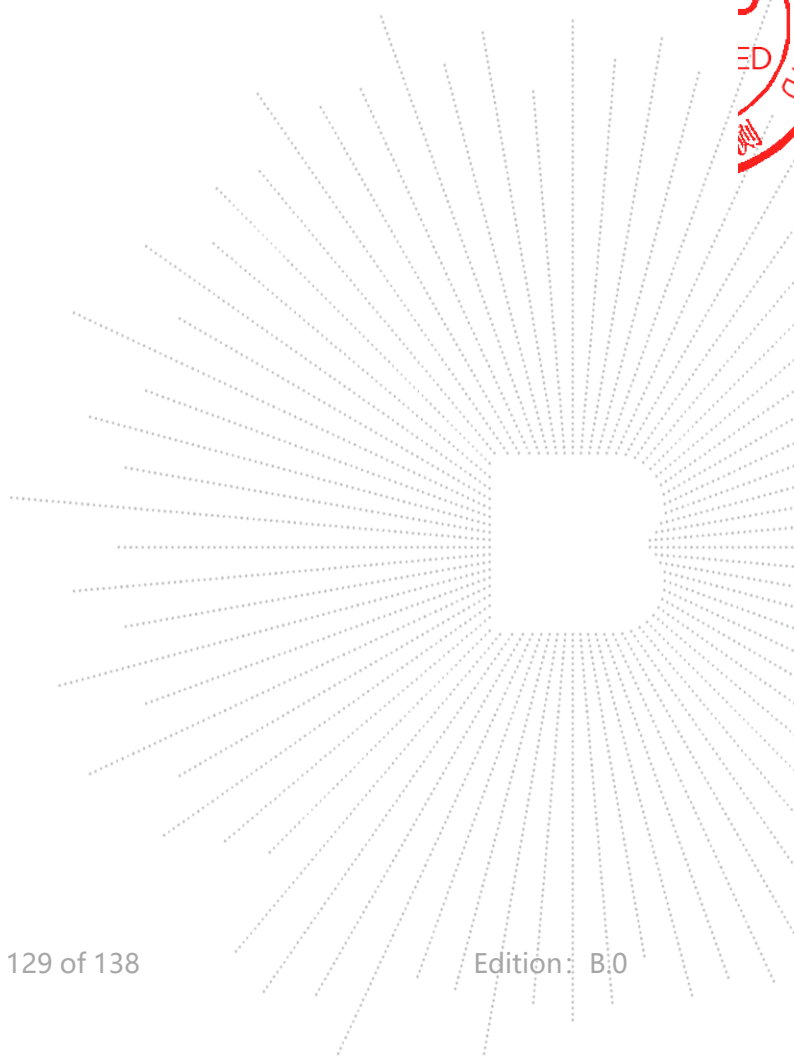
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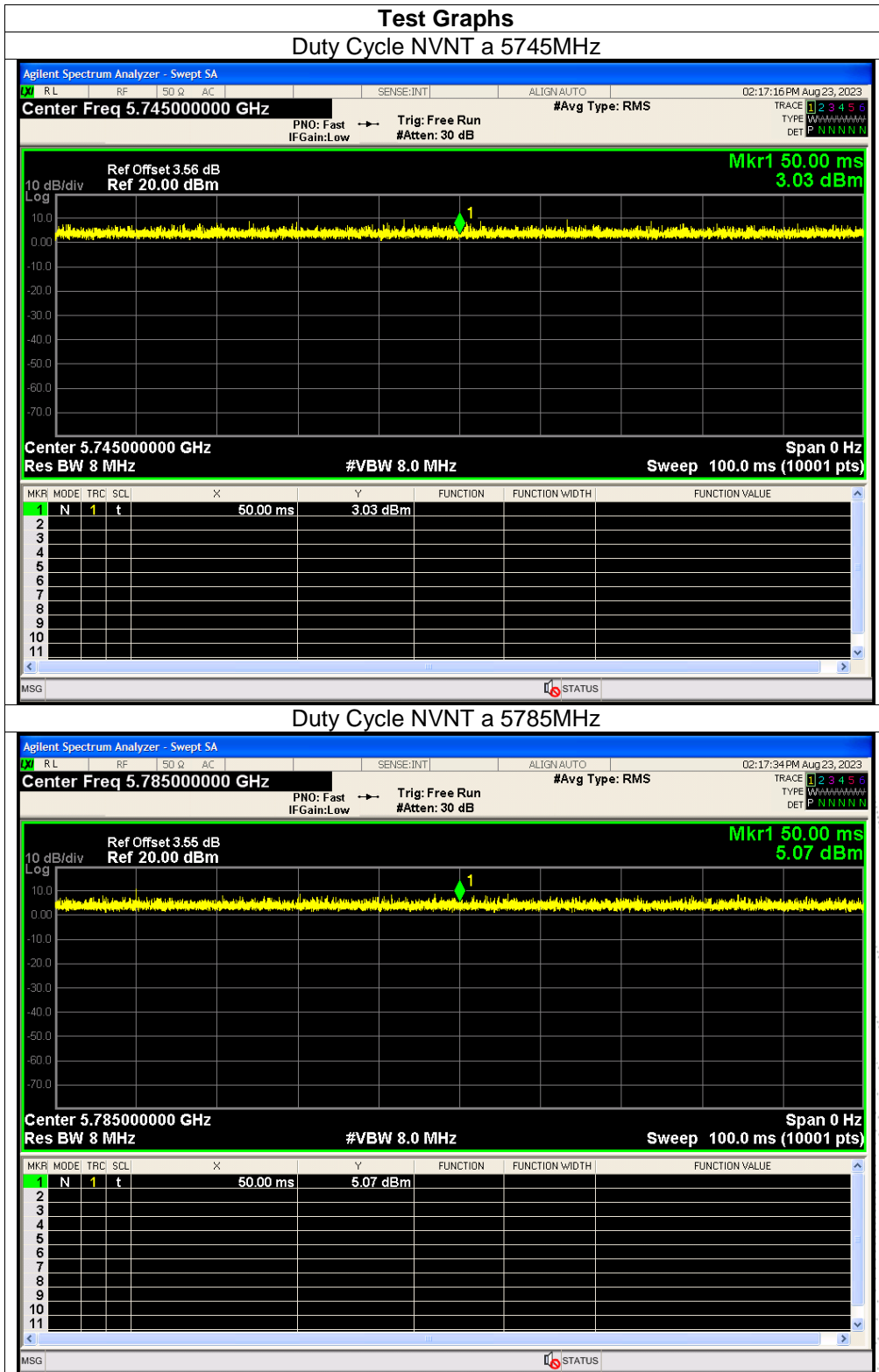


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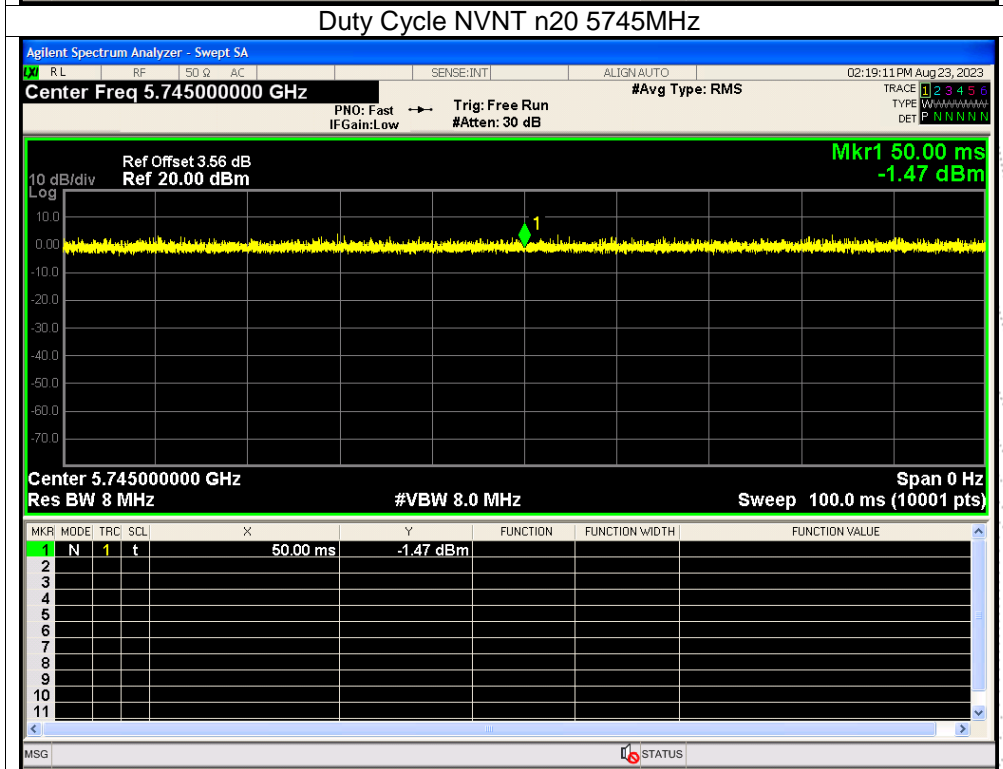
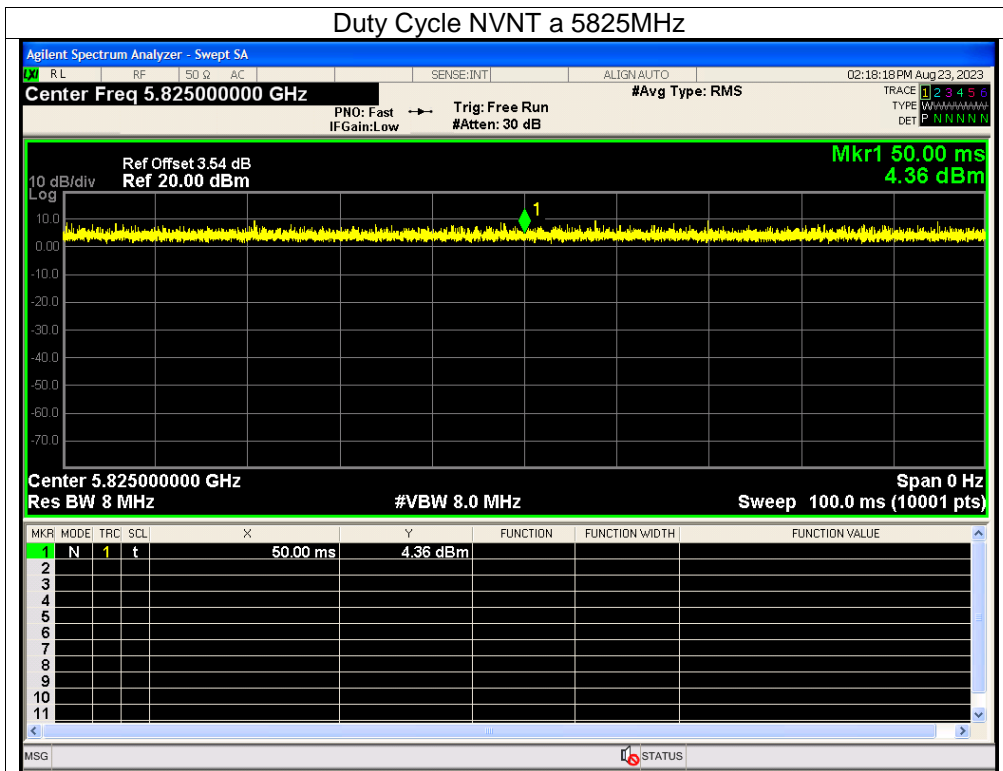


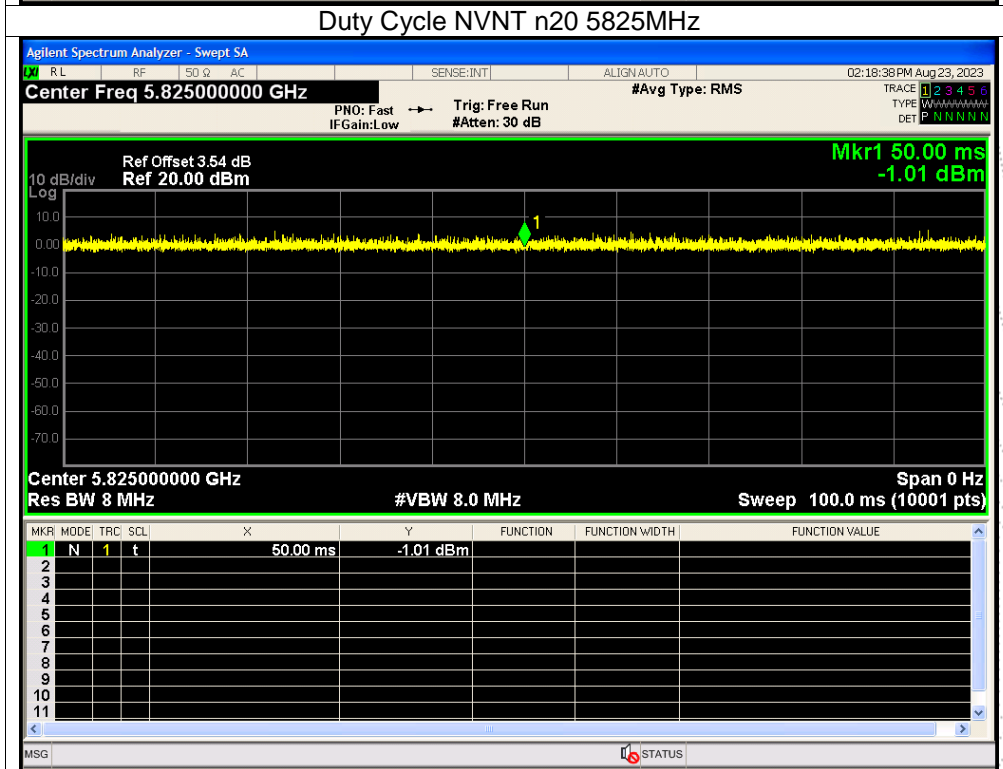
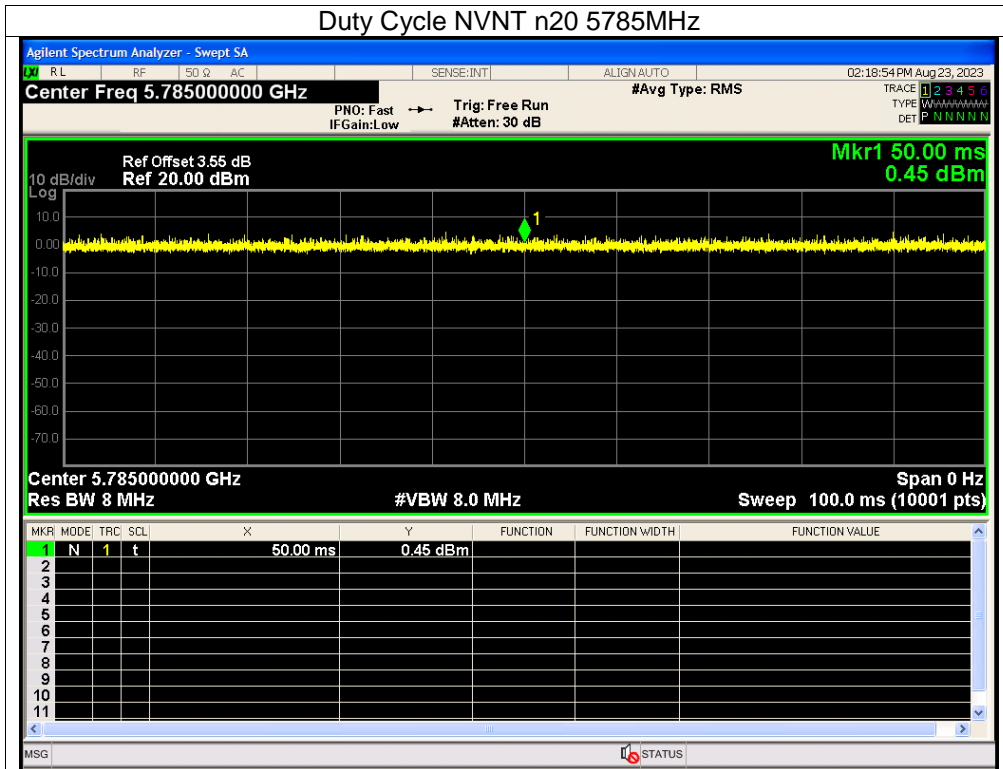
Condition	Mode	Frequency (MHz)	Duty Cycle (%)	Correction Factor (dB)	1/T (kHz)
NVNT	a	5745	100	0	0
NVNT	a	5785	100	0	0
NVNT	a	5825	100	0	0
NVNT	n20	5745	100	0	0
NVNT	n20	5785	100	0	0
NVNT	n20	5825	100	0	0





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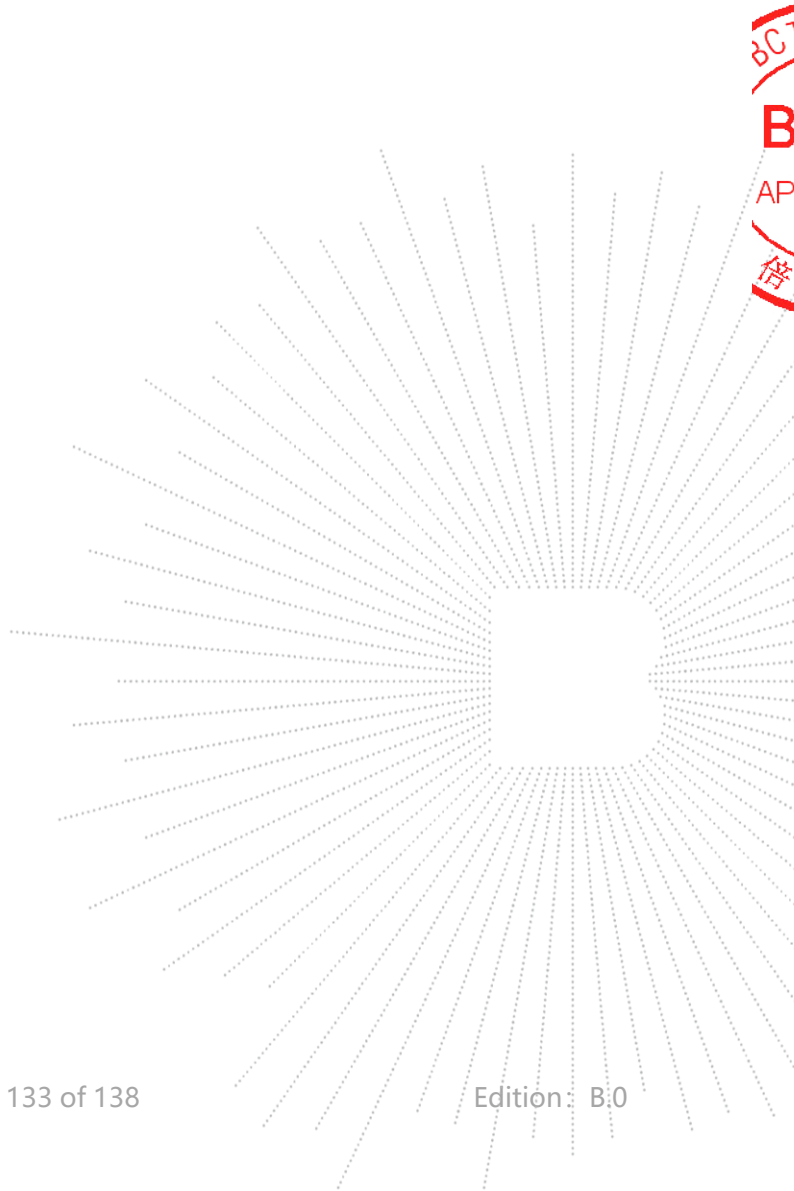
## 15. Antenna Requirement

### 15.1 Limit

15.203 requirement: For intentional device, according to 15.203: an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device.

### 15.2 Test Result

The EUT antenna is Internal antenna (antenna gain: 4.60dBi). It comply with the standard requirement.



### 16. EUT Photographs

EUT Photo 1



EUT Photo 2



NOTE: Appendix-Photographs Of EUT Constructional Details

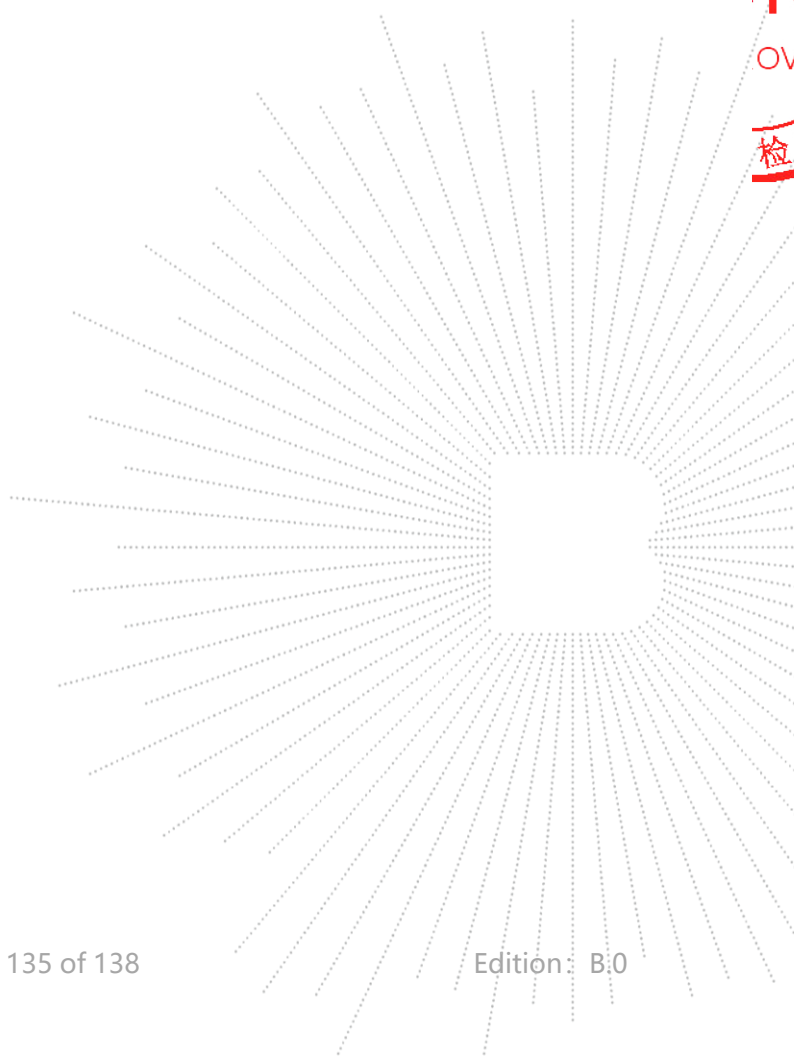
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### 17. EUT Test Setup Photographs

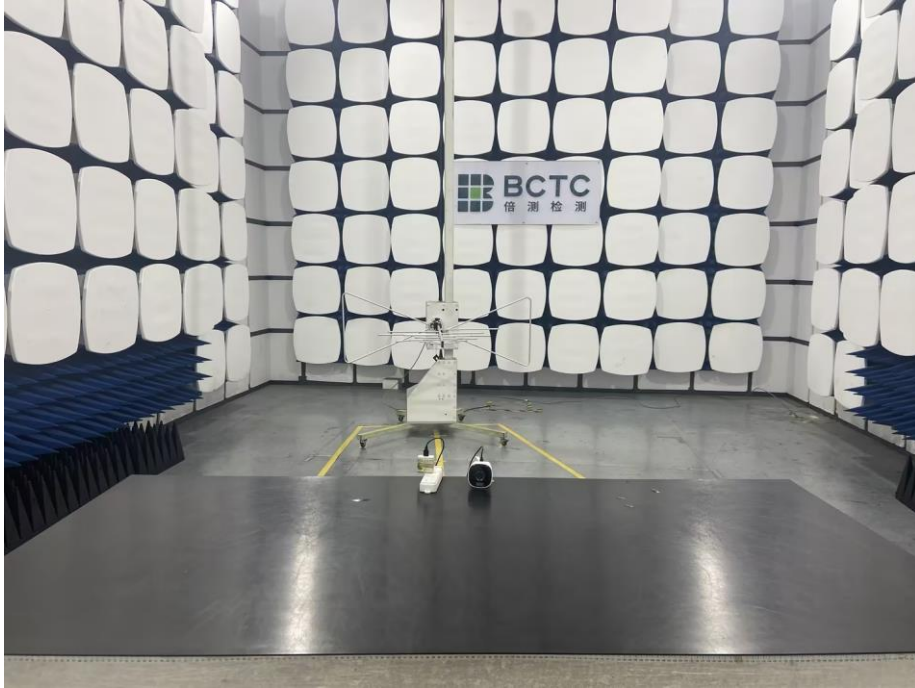
#### Conducted Emissions Photo



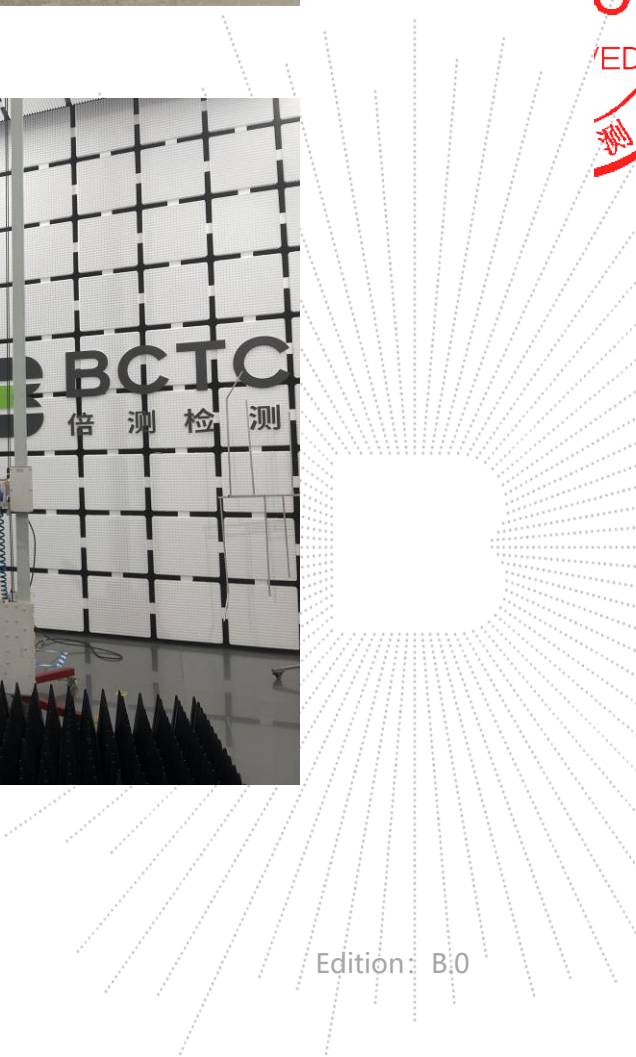
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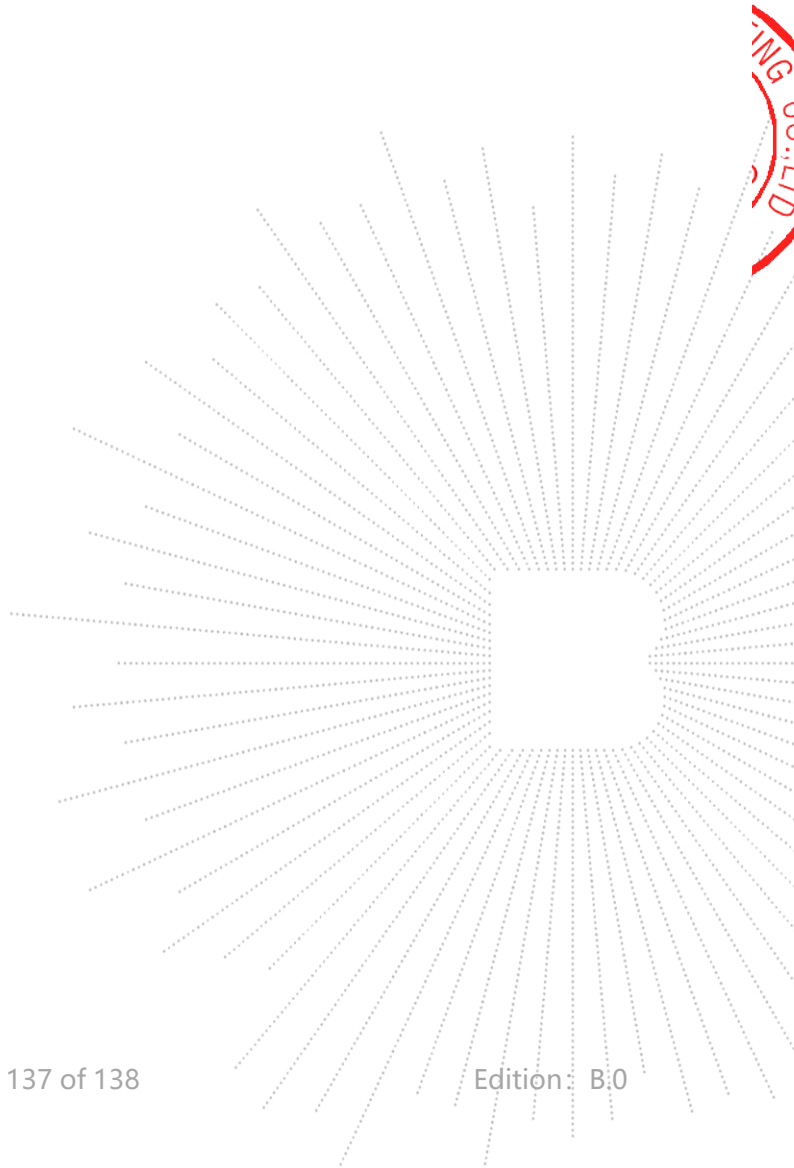
**Radiated Measurement Photos**



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**STATEMENT**

1. The equipment lists are traceable to the national reference standards.
2. The test report can not be partially copied unless prior written approval is issued from our lab.
3. The test report is invalid without the "special seal for inspection and testing".
4. The test report is invalid without the signature of the approver.
5. The test process and test result is only related to the Unit Under Test.
6. Sample information is provided by the client and the laboratory is not responsible for its authenticity.
7. The quality system of our laboratory is in accordance with ISO/IEC17025.
8. If there is any objection to this test report, the client should inform issuing laboratory within 15 days from the date of receiving test report.

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